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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	576
Number of Logic Elements/Cells	1368
Total RAM Bits	18432
Number of I/O	169
Number of Gates	30000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs30-4pq208c

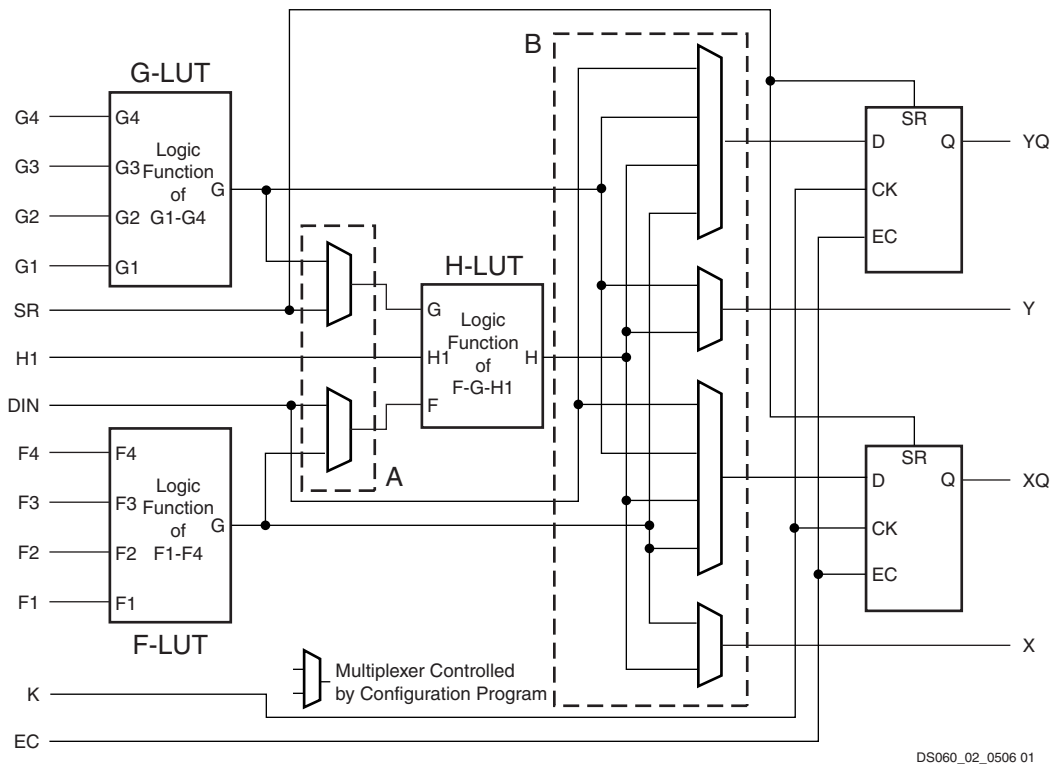


Figure 2: Spartan/XL Simplified CLB Logic Diagram (some features not shown)

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.

- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see [Figure 2](#)). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in [Global Signals: GSR and GTS, page 20](#).

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in [Table 2](#).

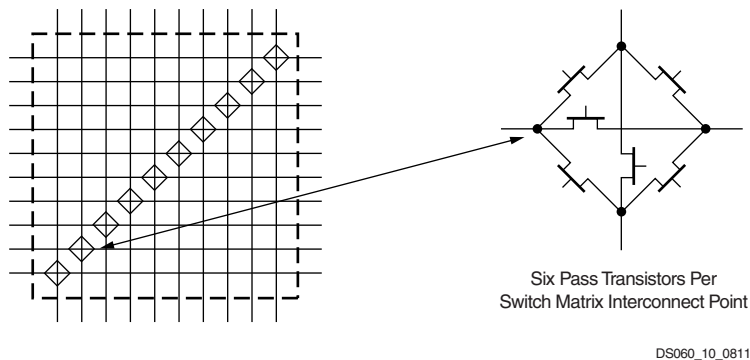


Figure 10: Programmable Switch Matrix

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

- The 16 x 1 single-port configuration contains a RAM array with 16 locations, each one-bit wide. One 4-bit address decoder determines the RAM location for write and read operations. There is one input for writing data and one output for reading data, all at the selected address.
- The (16 x 1) x 2 single-port configuration combines two 16 x 1 single-port configurations (each according to the preceding description). There is one data input, one data output and one address decoder for each array. These arrays can be addressed independently.
- The 32 x 1 single-port configuration contains a RAM array with 32 locations, each one-bit wide. There is one data input, one data output, and one 5-bit address decoder.
- The dual-port mode 16 x 1 configuration contains a RAM array with 16 locations, each one-bit wide. There are two 4-bit address decoders, one for each port. One port consists of an input for writing and an output for reading, all at a selected address. The other port consists of one output for reading from an independently selected address.

The appropriate choice of RAM configuration mode for a given design should be based on timing and resource requirements, desired functionality, and the simplicity of the design process. Selection criteria include the following: Whereas the 32 x 1 single-port, the (16 x 1) x 2 single-port, and the 16 x 1 dual-port configurations each use one entire CLB, the 16 x 1 single-port configuration uses only one half of a CLB. Due to its simultaneous read/write capability, the dual-port RAM can transfer twice as much data as the single-port RAM, which permits only one data operation at any given time.

CLB memory configuration options are selected by using the appropriate library symbol in the design entry.

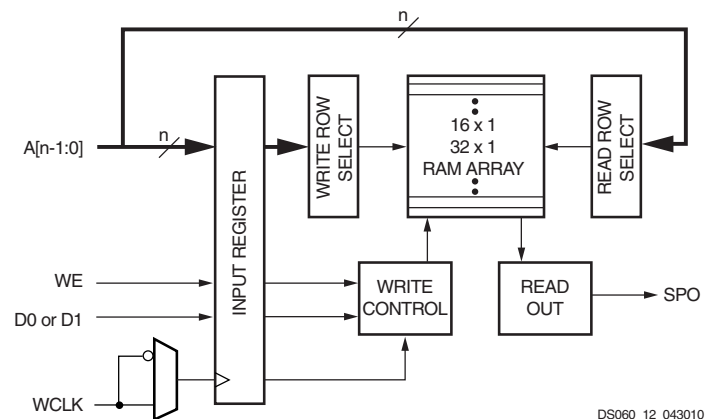
Single-Port Mode

There are three CLB memory configurations for the single-port RAM: 16 x 1, (16 x 1) x 2, and 32 x 1, the functional organization of which is shown in [Figure 12](#).

The single-port RAM signals and the CLB signals ([Figure 2](#), [page 4](#)) from which they are originally derived are shown in [Table 9](#).

Table 9: Single-Port RAM Signals

RAM Signal	Function	CLB Signal
D0 or D1	Data In	DIN or H1
A[3:0]	Address	F[4:1] or G[4:1]
A4 (32 x 1 only)	Address	H1
WE	Write Enable	SR
WCLK	Clock	K
SPO	Single Port Out (Data Out)	F _{OUT} or G _{OUT}



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Notes:

1. The (16 x 1) x 2 configuration combines two 16 x 1 single-port RAMs, each with its own independent address bus and data input. The same WE and WCLK signals are connected to both RAMs.
2. $n = 4$ for the 16 x 1 and (16 x 1) x 2 configurations. $n = 5$ for the 32 x 1 configuration.

Figure 12: Logic Diagram for the Single-Port RAM

Writing data to the single-port RAM is essentially the same as writing to a data register. It is an edge-triggered (synchronous) operation performed by applying an address to the A inputs and data to the D input during the active edge of WCLK while WE is High.

The timing relationships are shown in [Figure 13](#). The High logic level on WE enables the input data register for writing. The active edge of WCLK latches the address, input data, and WE signals. Then, an internal write pulse is generated that loads the data into the memory cell.

On-Chip Oscillator

Spartan/XL devices include an internal oscillator. This oscillator is used to clock the power-on time-out, for configuration memory clearing, and as the source of CCLK in Master configuration mode. The oscillator runs at a nominal 8 MHz frequency that varies with process, V_{CC} , and temperature. The output frequency falls between 4 MHz and 10 MHz.

The oscillator output is optionally available after configuration. Any two of four resynchronized taps of a built-in divider are also available. These taps are at the fourth, ninth, fourteenth and nineteenth bits of the divider. Therefore, if the primary oscillator output is running at the nominal 8 MHz, the user has access to an 8-MHz clock, plus any two of 500 kHz, 16 kHz, 490 Hz and 15 Hz. These frequencies can vary by as much as -50% or +25%.

These signals can be accessed by placing the OSC4 library element in a schematic or in HDL code. The oscillator is automatically disabled after configuration if the OSC4 symbol is not used in the design.

Global Signals: GSR and GTS

Global Set/Reset

A separate Global Set/Reset line, as shown in [Figure 3, page 5](#) for the CLB and [Figure 5, page 6](#) for the IOB, sets or clears each flip-flop during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, if in reset mode, it is reset by both SR and GSR.

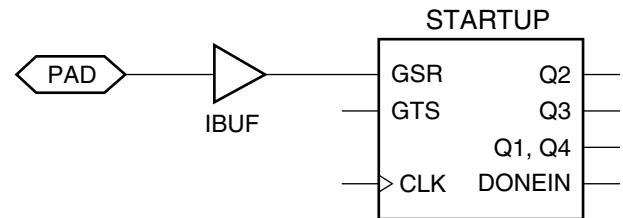
GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See [Figure 19.](#)) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the GSR signal. Alternatively, GSR can be driven from any internal node.

Global 3-State

A separate Global 3-state line (GTS) as shown in [Figure 6, page 7](#) forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. GTS does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. This is similar to what is shown in [Figure 19](#) for GSR except the IBUF would be

connected to GTS. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-state signal. Alternatively, GTS can be driven from any internal node.



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Figure 19: Symbols for Global Set/Reset

Boundary Scan

The "bed of nails" has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can embed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan compatible device. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The Spartan and Spartan-XL families implement IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in the Spartan/XL devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note: "Boundary Scan in FPGA Devices."

Even if the boundary scan symbol is used in a design, the input pins TMS, TCK, and TDI can still be used as inputs to be routed to internal logic. Care must be taken not to force the chip into an undesired boundary scan state by inadvertently applying boundary scan input patterns to these pins. The simplest way to prevent this is to keep TMS High, and then apply whatever signal is desired to TDI and TCK.

Avoiding Inadvertent Boundary Scan

If TMS or TCK is used as user I/O, care must be taken to ensure that at least one of these pins is held constant during configuration. In some applications, a situation may occur where TMS or TCK is driven during configuration. This may cause the device to go into boundary scan mode and disrupt the configuration process.

To prevent activation of boundary scan during configuration, do either of the following:

- TMS: Tie High to put the Test Access Port controller in a benign RESET state.
- TCK: Tie High or Low—do not toggle this clock input.

For more information regarding boundary scan, refer to the Xilinx Application Note, "Boundary Scan in FPGA Devices."

Boundary Scan Enhancements (Spartan-XL Family Only)

Spartan-XL devices have improved boundary scan functionality and performance in the following areas:

IDCODE: The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined. The use of the IDCODE enables selective configuration dependent on the FPGA found.

The IDCODE register has the following binary format:

```
vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc:ccc1
```

where

c = the company code (49h for Xilinx)

a = the array dimension in CLBs (ranges from 0Ah for XCS05XL to 1Ch for XCS40XL)

f = the family code (02h for Spartan-XL family)

v = the die version number

Table 13: IDCODEs Assigned to Spartan-XL FPGAs

FPGA	IDCODE
XCS05XL	0040A093h
XCS10XL	0040E093h
XCS20XL	00414093h
XCS30XL	00418093h
XCS40XL	0041C093h

Configuration State: The configuration state is available to JTAG controllers.

Configuration Disable: The JTAG port can be prevented from configuring the FPGA.

TCK Startup: TCK can now be used to clock the start-up block in addition to other user clocks.

CCLK Holdoff: Changed the requirement for Boundary Scan Configure or EXTEST to be issued prior to the release of INIT pin and CCLK cycling.

Reissue Configure: The Boundary Scan Configure can be reissued to recover from an unfinished attempt to configure the device.

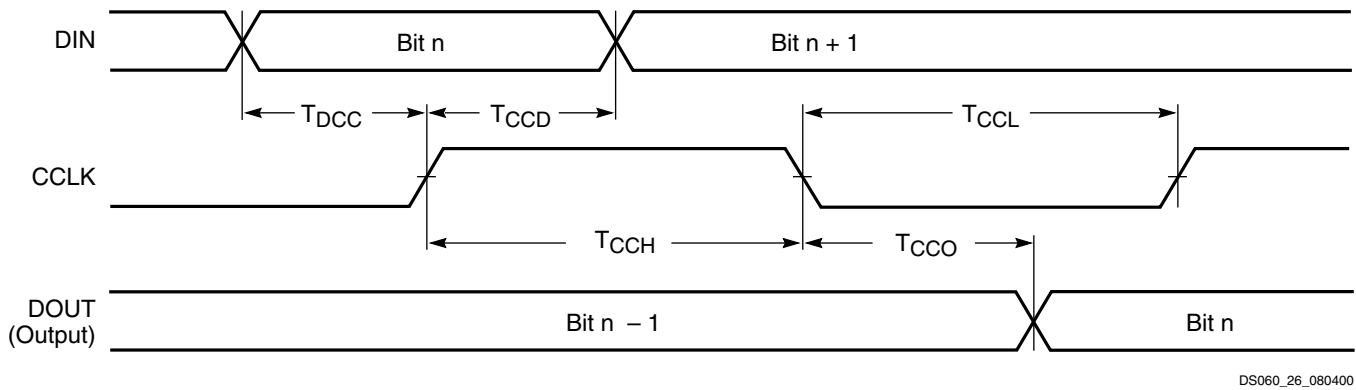
Bypass FF: Bypass FF and IOB is modified to provide DRCLOCK only during BYPASS for the bypass flip-flop, and during EXTEST or SAMPLE/PRELOAD for the IOB register.

Power-Down (Spartan-XL Family Only)

All Spartan/XL devices use a combination of efficient segmented routing and advanced process technology to provide low power consumption under all conditions. The 3.3V Spartan-XL family adds a dedicated active Low power-down pin (PWRDWN) to reduce supply current to 100 μ A typical. The PWRDWN pin takes advantage of one of the unused No Connect locations on the 5V Spartan device. The user must de-select the "5V Tolerant I/Os" option in the Configuration Options to achieve the specified Power Down current. The PWRDWN pin has a default internal pull-up resistor, allowing it to be left unconnected if unused.

V_{CC} must continue to be supplied during Power-down, and configuration data is maintained. When the PWRDWN pin is pulled Low, the input and output buffers are disabled. The inputs are internally forced to a logic Low level, including the MODE pins, DONE, CCLK, and TDO, and all internal pull-up resistors are turned off. The PROGRAM pin is not affected by Power Down. The GSR net is asserted during Power Down, initializing all the flip-flops to their start-up state.

PWRDWN has a minimum pulse width of 50 ns (Figure 23). On entering the Power-down state, the inputs will be disabled and the flip-flops set/reset, and then the outputs are disabled about 10 ns later. The user may prefer to assert the GTS or GSR signals before PWRDWN to affect the order of events. When the PWRDWN signal is returned High, the inputs will be enabled first, followed immediately by the release of the GSR signal initializing the flip-flops. About 10 ns later, the outputs will be enabled. Allow 50 ns after the release of PWRDWN before using the device.



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:

1. Configuration must be delayed until the \overline{INIT} pins of all daisy-chained FPGAs are High.

Figure 26: Slave Serial Mode Programming Switching Characteristics

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices

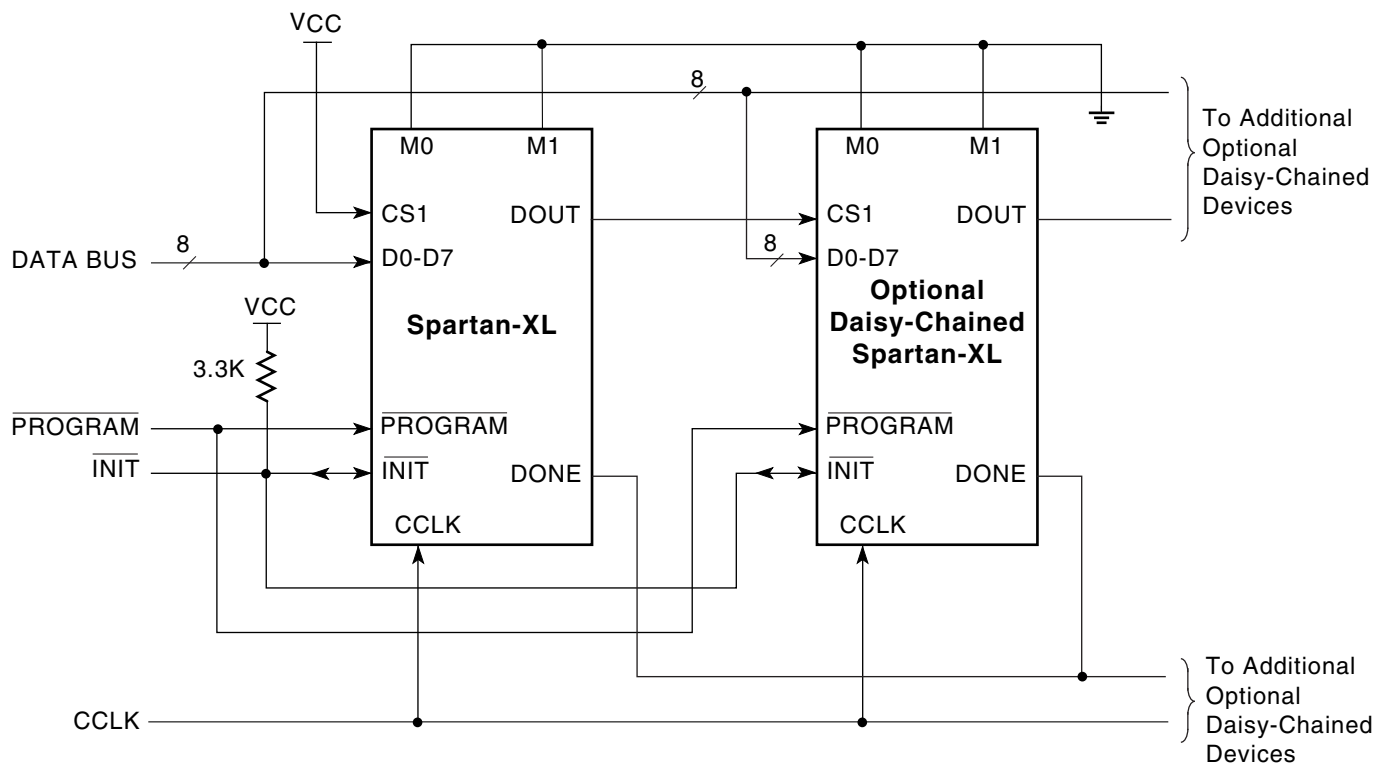
are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized

to the DONE pin. User I/Os for each device become active after the DONE pin for that device goes High. (The exact timing is determined by development system options.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device

in the chain has completed its configuration cycle. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured. Only devices supporting Express mode can be used to form an Express mode daisy chain.



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Figure 27: Express Mode Circuit Diagram

Table 17: Spartan/XL Program Data

Device	XCS05		XCS10		XCS20		XCS30		XCS40	
Max System Gates	5,000		10,000		20,000		30,000		40,000	
CLBs (Row x Col.)	100 (10 x 10)		196 (14 x 14)		400 (20 x 20)		576 (24 x 24)		784 (28 x 28)	
I/Os	80		112		160		192		205 ⁽⁴⁾	
Part Number	XCS05	XCS05XL	XCS10	XCS10XL	XCS20	XCS20XL	XCS30	XCS30XL	XCS40	XCS40XL
Supply Voltage	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V
Bits per Frame	126	127	166	167	226	227	266	267	306	307
Frames	428	429	572	573	788	789	932	933	1,076	1,077
Program Data	53,936	54,491	94,960	95,699	178,096	179,111	247,920	249,119	329,264	330,647
PROM Size (bits)	53,984	54,544	95,008	95,752	178,144	179,160	247,968	249,168	329,312	330,696
Express Mode PROM Size (bits)	-	79,072	-	128,488	-	221,056	-	298,696	-	387,856

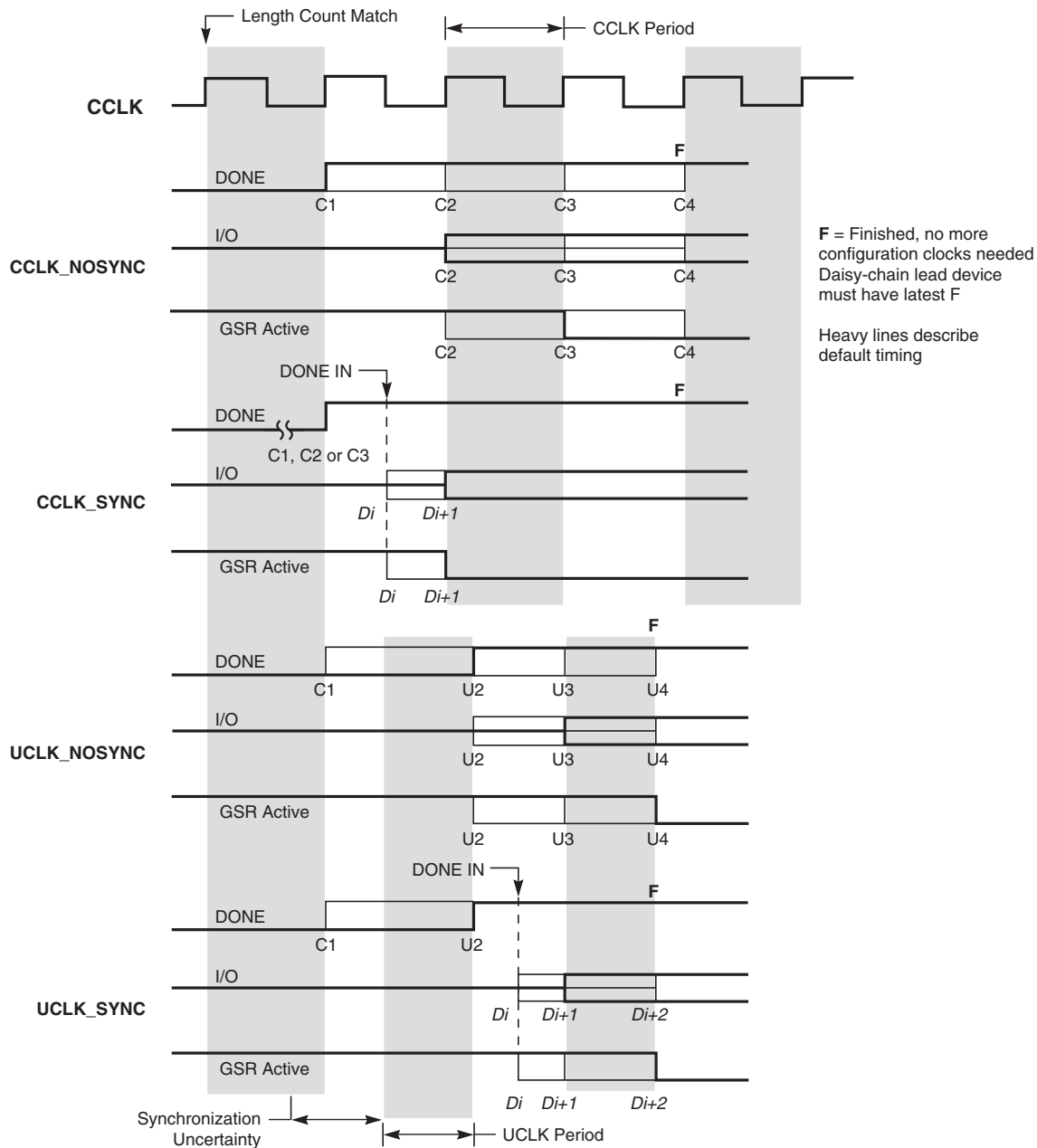
Notes:

- Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits (+1 for Spartan-XL device)
 Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1 (+ 1 for Spartan-XL device)
 Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits
 PROM Size = Program Data + 40 (header) + 8, rounded up to the nearest byte
- The user can add more "1" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value **must** be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.
- Express mode adds 57 (XCS05XL, XCS10XL), or 53 (XCS20XL, XCS30XL, XCS40XL) bits per frame, + additional start-up bits.
- XCS40XL provided 224 max I/O in CS280 package discontinued by [PDN2004-01](#).

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in [Figure 29](#). The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback

data is independent of the current device state. CLB outputs should not be included (Readback Capture option not used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.



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Figure 31: Start-up Timing

Configuration Through the Boundary Scan Pins

Spartan/XL devices can be configured through the boundary scan pins. The basic procedure is as follows:

- Power up the FPGA with $\overline{\text{INIT}}$ held Low (or drive the PROGRAM pin Low for more than 300 ns followed by a High while holding $\overline{\text{INIT}}$ Low). Holding $\overline{\text{INIT}}$ Low allows enough time to issue the CONFIG command to the FPGA. The pin can be used as I/O after configuration if a resistor is used to hold $\overline{\text{INIT}}$ Low.
- Issue the CONFIG command to the TMS input.

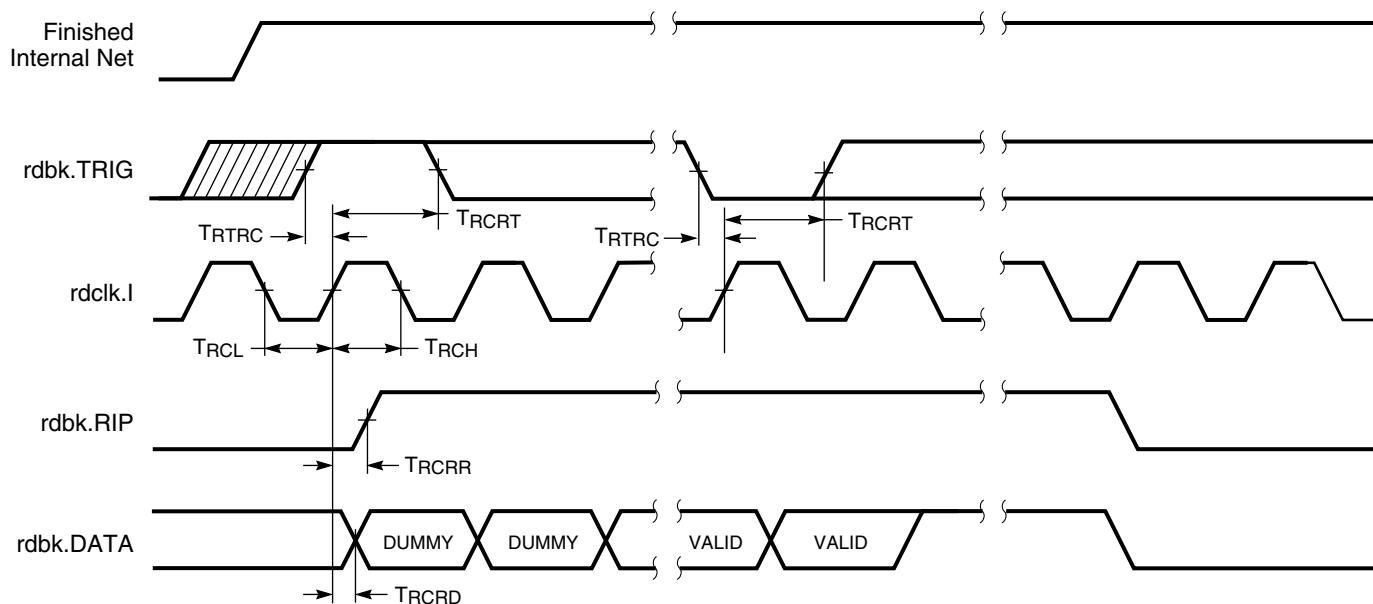
- Wait for $\overline{\text{INIT}}$ to go High.
- Sequence the boundary scan Test Access Port to the SHIFT-DR state.
- Toggle TCK to clock data into TDI pin.

The user must account for all TCK clock cycles after $\overline{\text{INIT}}$ goes High, as all of these cycles affect the Length Count compare.

For more detailed information, refer to the Xilinx application note, "Boundary Scan in FPGA Devices." This application note applies to Spartan and Spartan-XL devices.

Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.



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Figure 33: Spartan and Spartan-XL Readback Timing Diagram

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T_{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T_{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T_{RCRD}	rdclk.I	rdbk.DATA delay	-	250	ns
T_{RCRR}		rdbk.RIP delay	-	250	ns
T_{RCH}		High time	250	500	ns
T_{RCL}		Low time	250	500	ns

Notes:

1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (continued)

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Dual-Port RAM Synchronous (Edge-Triggered) Write Operation Characteristics

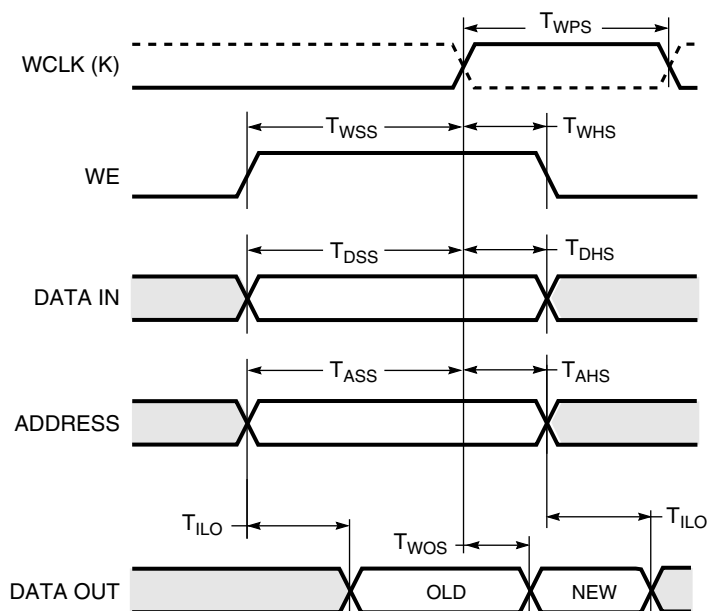
Symbol	Dual Port RAM	Size ⁽¹⁾	-4		-3		Units
			Min	Max	Min	Max	
Write Operation							
T _{WCDS}	Address write cycle time (clock K period)	16x1	8.0	-	11.6	-	ns
T _{WPDS}	Clock K pulse width (active edge)	16x1	4.0	-	5.8	-	ns
T _{ASDS}	Address setup time before clock K	16x1	1.5	-	2.1	-	ns
T _{AHDS}	Address hold time after clock K	16x1	0	-	0	-	ns
T _{DSDS}	DIN setup time before clock K	16x1	1.5	-	1.6	-	ns
T _{DHDS}	DIN hold time after clock K	16x1	0	-	0	-	ns
T _{WSDS}	WE setup time before clock K	16x1	1.5	-	1.6	-	ns
T _{WHDS}	WE hold time after clock K	16x1	0	-	0	-	ns
T _{WODS}	Data valid after clock K	16x1	-	6.5	-	7.0	ns

Notes:

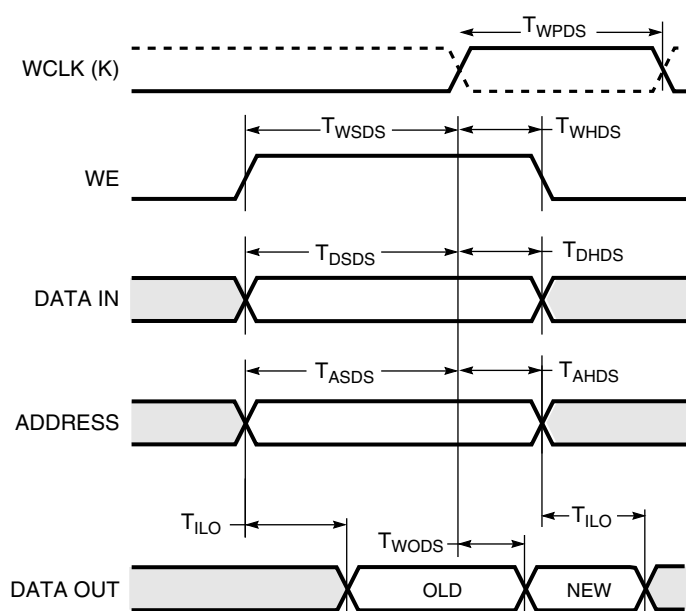
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Timing

Single Port



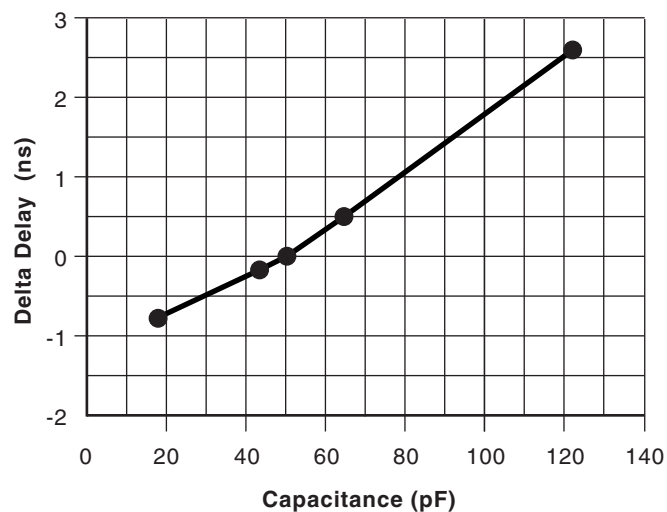
Dual Port



DS060_34_011300

Capacitive Load Factor

Figure 34 shows the relationship between I/O output delay and load capacitance. It allows a user to adjust the specified output delay if the load capacitance is different than 50 pF. For example, if the actual load capacitance is 120 pF, add 2.5 ns to the specified delay. If the load capacitance is 20 pF, subtract 0.8 ns from the specified output delay. Figure 34 is usable over the specified operating conditions of voltage and temperature and is independent of the output slew rate control.



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Figure 34: Delay Factor at Various Capacitive Loads

Spartan Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Setup Times - TTL Inputs ⁽¹⁾							
T _{ECIK}	Clock Enable (EC) to Clock (IK), no delay	All devices	1.6	-	2.1	-	ns
T _{PICK}	Pad to Clock (IK), no delay	All devices	1.5	-	2.0	-	ns
Hold Times							
T _{IKEC}	Clock Enable (EC) to Clock (IK), no delay	All devices	0.0	-	0.9	-	ns
	All Other Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays - TTL Inputs ⁽¹⁾							
T _{PID}	Pad to I1, I2	All devices	-	1.5	-	2.0	ns
T _{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.8	-	3.6	ns
T _{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	2.7	-	2.8	ns
T _{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	3.2	-	3.9	ns
Delay Adder for Input with Delay Option							
T _{Delay}	T _{ECIKD} = T _{ECIK} + T _{Delay} T _{PICKD} = T _{PICK} + T _{Delay} T _{PDLI} = T _{PLI} + T _{Delay}	XCS05	3.6	-	4.0	-	ns
		XCS10	3.7	-	4.1	-	ns
		XCS20	3.8	-	4.2	-	ns
		XCS30	4.5	-	5.0	-	ns
		XCS40	5.5	-	5.5	-	ns
Global Set/Reset							
T _{MRW}	Minimum GSR pulse width	All devices	11.5	-	13.5	-	ns
T _{RRI}	Delay from GSR input to any Q	XCS05	-	9.0	-	11.3	ns
		XCS10	-	9.5	-	11.9	ns
		XCS20	-	10.0	-	12.5	ns
		XCS30	-	10.5	-	13.1	ns
		XCS40	-	11.0	-	13.8	ns

Notes:

1. Delay adder for CMOS Inputs option: for -3 speed grade, add 0.4 ns; for -4 speed grade, add 0.2 ns.
2. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
3. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size ⁽¹⁾	Speed Grade				Units
			-5		-4		
			Min	Max	Min	Max	
Write Operation							
T _{WCS}	Address write cycle time (clock K period)	16x2	7.7	-	8.4	-	ns
T _{WCTS}		32x1	7.7	-	8.4	-	ns
T _{WPS}	Clock K pulse width (active edge)	16x2	3.1	-	3.6	-	ns
T _{WPTS}		32x1	3.1	-	3.6	-	ns
T _{ASS}	Address setup time before clock K	16x2	1.3	-	1.5	-	ns
T _{ASTS}		32x1	1.5	-	1.7	-	ns
T _{DSS}	DIN setup time before clock K	16x2	1.5	-	1.7	-	ns
T _{DSTS}		32x1	1.8	-	2.1	-	ns
T _{WSS}	WE setup time before clock K	16x2	1.4	-	1.6	-	ns
T _{WSTS}		32x1	1.3	-	1.5	-	ns
	All hold times after clock K	16x2	0.0	-	0.0	-	ns
T _{WOS}	Data valid after clock K	32x1	-	4.5	-	5.3	ns
T _{WOTS}		16x2	-	5.4	-	6.3	ns
Read Operation							
T _{RC}	Address read cycle time	16x2	2.6	-	3.1	-	ns
T _{RCT}		32x1	3.8	-	5.5	-	ns
T _{ILO}	Data Valid after address change (no Write Enable)	16x2	-	1.0	-	1.1	ns
T _{IHO}		32x1	-	1.7	-	2.0	ns
T _{ICK}	Address setup time before clock K	16x2	0.6	-	0.7	-	ns
T _{IHCK}		32x1	1.3	-	1.6	-	ns

Notes:

1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan-XL Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case oper-

ating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading.

Spartan-XL Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade		Units
			-5	-4	
			Max	Max	
Global Clock to Output using OFF					
T _{ICKOF}	Fast	XCS05XL	4.6	5.2	ns
		XCS10XL	4.9	5.5	ns
		XCS20XL	5.2	5.8	ns
		XCS30XL	5.5	6.2	ns
		XCS40XL	5.8	6.5	ns
Slew Rate Adjustment					
T _{SLOW}	For Output SLOW option add	All Devices	1.5	1.7	ns

Notes:

1. Output delays are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load.
3. OFF = Output Flip Flop

Pin Descriptions

There are three types of pins in the Spartan/XL devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with the I/O pull-up resistor network activated. After configuration, if an IOB is unused it is configured as an input with the I/O pull-up resistor network remaining activated.

Any user I/O can be configured to drive the Global Set/Reset net GSR or the global three-state net GTS. See **Global Signals: GSR and GTS**, page 20 for more information.

Device pins for Spartan/XL devices are described in **Table 18**.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pin-outs as the standard package options.

Table 18: Pin Descriptions

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Permanently Dedicated Pins			
V _{CC}	X	X	Eight or more (depending on package) connections to the nominal +5V supply voltage (+3.3V for Spartan-XL devices). All must be connected, and each must be decoupled with a 0.01 – 0.1 μ F capacitor to Ground.
GND	X	X	Eight or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master mode and is an input in Slave mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High or Low time restriction on Spartan/XL devices, except during Readback. See Violating the Maximum High and Low Time Specification for the Readback Clock , page 39 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an open-drain output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs. The optional pull-up resistor is selected as an option in the program that creates the configuration bitstream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	$\overline{\text{PROGRAM}}$ is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When $\overline{\text{PROGRAM}}$ goes High, the FPGA finishes the current clear cycle and executes another complete clear cycle, before it goes into a WAIT state and releases $\overline{\text{INIT}}$. The $\overline{\text{PROGRAM}}$ pin has a permanent weak pull-up, so it need not be externally pulled up to VCC.
MODE (Spartan) M0, M1 (Spartan-XL)	I	X	The Mode input(s) are sampled after $\overline{\text{INIT}}$ goes High to determine the configuration mode to be used. During configuration, these pins have a weak pull-up resistor. For the most popular configuration mode, Slave Serial, the mode pins can be left unconnected. For Master Serial mode, connect the Mode/M0 pin directly to system ground.

Device-Specific Pinout Tables

Device-specific tables include all packages for each Spartan and Spartan-XL device. They follow the pad locations around the die, and include boundary scan register locations.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pinouts as the standard package options.

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84 ⁽⁴⁾	VQ100	Bndry Scan
VCC	P2	P89	-
I/O	P3	P90	32
I/O	P4	P91	35
I/O	-	P92	38
I/O	-	P93	41
I/O	P5	P94	44
I/O	P6	P95	47
I/O	P7	P96	50
I/O	P8	P97	53
I/O	P9	P98	56
I/O, SGCK1 ⁽¹⁾ , GCK8 ⁽²⁾	P10	P99	59
VCC	P11	P100	-
GND	P12	P1	-
I/O, PGCK1 ⁽¹⁾ , GCK1 ⁽²⁾	P13	P2	62
I/O	P14	P3	65
I/O, TDI	P15	P4	68
I/O, TCK	P16	P5	71
I/O, TMS	P17	P6	74
I/O	P18	P7	77
I/O	-	P8	83
I/O	P19	P9	86
I/O	P20	P10	89
GND	P21	P11	-
VCC	P22	P12	-
I/O	P23	P13	92
I/O	P24	P14	95
I/O	-	P15	98
I/O	P25	P16	104
I/O	P26	P17	107
I/O	P27	P18	110
I/O	-	P19	113
I/O	P28	P20	116
I/O, SGCK2 ⁽¹⁾ , GCK2 ⁽²⁾	P29	P21	119
Not Connected ⁽¹⁾ , M1 ⁽²⁾	P30	P22	122
GND	P31	P23	-
MODE ⁽¹⁾ , M0 ⁽²⁾	P32	P24	125
VCC	P33	P25	-

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84 ⁽⁴⁾	VQ100	Bndry Scan
Not Connected ⁽¹⁾ , PWRDWN ⁽²⁾	P34	P26	126 ⁽¹⁾
I/O, PGCK2 ⁽¹⁾ , GCK3 ⁽²⁾	P35	P27	127 ⁽³⁾
I/O (HDC)	P36	P28	130 ⁽³⁾
I/O	-	P29	133 ⁽³⁾
I/O (LDC)	P37	P30	136 ⁽³⁾
I/O	P38	P31	139 ⁽³⁾
I/O	P39	P32	142 ⁽³⁾
I/O	-	P33	145 ⁽³⁾
I/O	-	P34	148 ⁽³⁾
I/O	P40	P35	151 ⁽³⁾
I/O (INIT)	P41	P36	154 ⁽³⁾
VCC	P42	P37	-
GND	P43	P38	-
I/O	P44	P39	157 ⁽³⁾
I/O	P45	P40	160 ⁽³⁾
I/O	-	P41	163 ⁽³⁾
I/O	-	P42	166 ⁽³⁾
I/O	P46	P43	169 ⁽³⁾
I/O	P47	P44	172 ⁽³⁾
I/O	P48	P45	175 ⁽³⁾
I/O	P49	P46	178 ⁽³⁾
I/O	P50	P47	181 ⁽³⁾
I/O, SGCK3 ⁽¹⁾ , GCK4 ⁽²⁾	P51	P48	184 ⁽³⁾
GND	P52	P49	-
DONE	P53	P50	-
VCC	P54	P51	-
PROGRAM	P55	P52	-
I/O (D7 ⁽²⁾)	P56	P53	187 ⁽³⁾
I/O, PGCK3 ⁽¹⁾ , GCK5 ⁽²⁾	P57	P54	190 ⁽³⁾
I/O (D6 ⁽²⁾)	P58	P55	193 ⁽³⁾
I/O	-	P56	196 ⁽³⁾
I/O (D5 ⁽²⁾)	P59	P57	199 ⁽³⁾
I/O	P60	P58	202 ⁽³⁾
I/O	-	P59	205 ⁽³⁾
I/O	-	P60	208 ⁽³⁾
I/O (D4 ⁽²⁾)	P61	P61	211 ⁽³⁾
I/O	P62	P62	214 ⁽³⁾
VCC	P63	P63	-
GND	P64	P64	-
I/O (D3 ⁽²⁾)	P65	P65	217 ⁽³⁾
I/O	P66	P66	220 ⁽³⁾
I/O	-	P67	223 ⁽³⁾
I/O (D2 ⁽²⁾)	P67	P68	229 ⁽³⁾
I/O	P68	P69	232 ⁽³⁾
I/O (D1 ⁽²⁾)	P69	P70	235 ⁽³⁾

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144 ^(2,4)	TQ144	PQ208	Bndry Scan
I/O	-	F4	P13	P21	170
I/O	P8	F3	P14	P22	173
I/O	P9	F2	P15	P23	176
I/O	P10	F1	P16	P24	179
GND	P11	G2	P17	P25	-
VCC	P12	G1	P18	P26	-
I/O	P13	G3	P19	P27	182
I/O	P14	G4	P20	P28	185
I/O	P15	H1	P21	P29	188
I/O	-	H2	P22	P30	191
I/O	-	-	-	P31	194
I/O	-	-	-	P32	197
VCC ⁽²⁾	-	-	-	P33	-
I/O	P16	H3	P23	P34	200
I/O	P17	H4	P24	P35	203
I/O	-	J1	P25	P36	206
I/O	-	J2	P26	P37	209
GND	-	J3	P27	P38	-
I/O	-	-	-	P40	212
I/O	-	-	-	P41	215
I/O	-	-	-	P42	218
I/O	-	-	-	P43	221
I/O	P18	J4	P28	P44	224
I/O	P19	K1	P29	P45	227
I/O	-	K2	P30	P46	230
I/O	-	K3	P31	P47	233
I/O	P20	L1	P32	P48	236
I/O, SGCK2 ⁽¹⁾ , GCK2 ⁽²⁾	P21	L2	P33	P49	239
Not Connected ⁽¹⁾ M1 ⁽²⁾	P22	L3	P34	P50	242
GND	P23	M1	P35	P51	-
MODE ⁽¹⁾ , M0 ⁽²⁾	P24	M2	P36	P52	245
VCC	P25	N1	P37	P53	-
Not Connected ⁽¹⁾ PWRDWN ⁽²⁾	P26	N2	P38	P54	246 ⁽¹⁾
I/O, PGCK2 ⁽¹⁾ , GCK3 ⁽²⁾	P27	M3	P39	P55	247 ⁽³⁾
I/O (HDC)	P28	N3	P40	P56	250 ⁽³⁾
I/O	-	K4	P41	P57	253 ⁽³⁾
I/O	-	L4	P42	P58	256 ⁽³⁾
I/O	P29	M4	P43	P59	259 ⁽³⁾

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144 ^(2,4)	TQ144	PQ208	Bndry Scan
I/O (LDC)	P30	N4	P44	P60	262 ⁽³⁾
I/O	-	-	-	P61	265 ⁽³⁾
I/O	-	-	-	P62	268 ⁽³⁾
I/O	-	-	-	P63	271 ⁽³⁾
I/O	-	-	-	P64	274 ⁽³⁾
GND	-	K5	P45	P66	-
I/O	-	L5	P46	P67	277 ⁽³⁾
I/O	-	M5	P47	P68	280 ⁽³⁾
I/O	P31	N5	P48	P69	283 ⁽³⁾
I/O	P32	K6	P49	P70	286 ⁽³⁾
VCC ⁽²⁾	-	-	-	P71	-
I/O	-	-	-	P72	289 ⁽³⁾
I/O	-	-	-	P73	292 ⁽³⁾
I/O	P33	L6	P50	P74	295 ⁽³⁾
I/O	P34	M6	P51	P75	298 ⁽³⁾
I/O	P35	N6	P52	P76	301 ⁽³⁾
I/O (INIT)	P36	M7	P53	P77	304 ⁽³⁾
VCC	P37	N7	P54	P78	-
GND	P38	L7	P55	P79	-
I/O	P39	K7	P56	P80	307 ⁽³⁾
I/O	P40	N8	P57	P81	310 ⁽³⁾
I/O	P41	M8	P58	P82	313 ⁽³⁾
I/O	P42	L8	P59	P83	316 ⁽³⁾
I/O	-	-	-	P84	319 ⁽³⁾
I/O	-	-	-	P85	322 ⁽³⁾
VCC ⁽²⁾	-	-	-	P86	-
I/O	P43	K8	P60	P87	325 ⁽³⁾
I/O	P44	N9	P61	P88	328 ⁽³⁾
I/O	-	M9	P62	P89	331 ⁽³⁾
I/O	-	L9	P63	P90	334 ⁽³⁾
GND	-	K9	P64	P91	-
I/O	-	-	-	P93	337 ⁽³⁾
I/O	-	-	-	P94	340 ⁽³⁾
I/O	-	-	-	P95	343 ⁽³⁾
I/O	-	-	-	P96	346 ⁽³⁾
I/O	P45	N10	P65	P97	349 ⁽³⁾
I/O	P46	M10	P66	P98	352 ⁽³⁾
I/O	-	L10	P67	P99	355 ⁽³⁾
I/O	-	N11	P68	P100	358 ⁽³⁾
I/O	P47	M11	P69	P101	361 ⁽³⁾
I/O, SGCK3 ⁽¹⁾ , GCK4 ⁽²⁾	P48	L11	P70	P102	364 ⁽³⁾
GND	P49	N12	P71	P103	-
DONE	P50	M12	P72	P104	-
VCC	P51	N13	P73	P105	-

CS280

VCC Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-
Not Connected Pins					
A4	A12	C8	C12	C15	D1
D2	D5	D8	D17	D18	E15
H2	H3	H18	H19	L4	M1
M16	M18	R2	R4	R5	R15
R17	T8	T15	U5	V8	V12
W12	W16	-	-	-	-
Not Connected Pins (VCC in XCS40XL)					
B5	B15	E3	E18	R3	R18
V5	V15	-	-	-	-

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XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
VCC	P183	P212	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P184	P213	C10	D10	86
I/O	P185	P214	D10	E10	89
I/O	P186	P215	A9	A9	92
I/O	P187	P216	B9	B9	95
I/O	P188	P217	C9	C9	98
I/O	P189	P218	D9	D9	101
I/O	P190	P220	A8	A8	104
I/O	P191	P221	B8	B8	107
I/O	-	-	C8	C8	110
I/O	-	-	A7	D8	113
VCC	P192	P222	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	-	P223	A6	B7	116
I/O	-	P224	C7	C7	119
I/O	P193	P225	B6	D7	122
I/O	P194	P226	A5	A6	125
GND	P195	P227	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P196	P228	C6	B6	128
I/O	P197	P229	B5	C6	131
I/O	P198	P230	A4	D6	134
I/O	P199	P231	C5	E6	137

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
I/O	P200	P232	B4	A5	140
I/O	P201	P233	A3	C5	143
I/O	-	-	-	D5	146
I/O	-	-	-	A4	149
I/O	P202	P234	D5	B4	152
I/O	P203	P235	C4	C4	155
I/O	P204	P236	B3	A3	158
I/O	P205	P237	B2	A2	161
I/O	P206	P238	A2	B3	164
I/O, SGCK1 ⁽¹⁾ , GCK8 ⁽²⁾	P207	P239	C3	B2	167
VCC	P208	P240	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
GND	P1	P1	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O, PGCK1 ⁽¹⁾ , GCK1 ⁽²⁾	P2	P2	B1	C3	170
I/O	P3	P3	C2	C2	173
I/O	P4	P4	D2	B1	176
I/O	P5	P5	D3	C1	179
I/O, TDI	P6	P6	E4	D4	182
I/O, TCK	P7	P7	C1	D3	185
I/O	-	-	-	D2	188
I/O	-	-	-	D1	191
I/O	P8	P8	D1	E2	194
I/O	P9	P9	E3	E4	197
I/O	P10	P10	E2	E1	200
I/O	P11	P11	E1	F5	203
I/O	P12	P12	F3	F3	206
I/O	-	P13	F2	F2	209
GND	P13	P14	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P14	P15	G3	F4	212
I/O	P15	P16	G2	F1	215
I/O, TMS	P16	P17	G1	G3	218
I/O	P17	P18	H3	G2	221
VCC	P18	P19	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	-	P20	H2	G4	224
I/O	-	P21	H1	H1	227
I/O	-	-	J4	H3	230
I/O	-	-	J3	H2	233
I/O	P19	P23	J2	H4	236
I/O	P20	P24	J1	J1	239
I/O	P21	P25	K2	J2	242
I/O	P22	P26	K3	J3	245
I/O	P23	P27	K1	J4	248
I/O	P24	P28	L1	K1	251

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
GND	P25	P29	GND ⁽⁴⁾	GND ⁽⁴⁾	-
VCC	P26	P30	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P27	P31	L2	K3	254
I/O	P28	P32	L3	K4	257
I/O	P29	P33	L4	K5	260
I/O	P30	P34	M1	L1	263
I/O	P31	P35	M2	L2	266
I/O	P32	P36	M3	L3	269
I/O	-	-	M4	L4	272
I/O	-	-	-	M1	275
I/O	-	P38	N1	M2	278
I/O	-	P39	N2	M3	281
VCC	P33	P40	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P34	P41	P1	N1	284
I/O	P35	P42	P2	N2	287
I/O	P36	P43	R1	N3	290
I/O	P37	P44	P3	N4	293
GND	P38	P45	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	-	P46	T1	P1	296
I/O	P39	P47	R3	P2	299
I/O	P40	P48	T2	P3	302
I/O	P41	P49	U1	P4	305
I/O	P42	P50	T3	P5	308
I/O	P43	P51	U2	R1	311
I/O	-	-	-	R2	314
I/O	-	-	-	R4	317
I/O	P44	P52	V1	T1	320
I/O	P45	P53	T4	T2	323
I/O	P46	P54	U3	T3	326
I/O	P47	P55	V2	U1	329
I/O	P48	P56	W1	V1	332
I/O, SGCK2 ⁽¹⁾ , GCK2 ⁽²⁾	P49	P57	V3	U2	335
Not Connected ⁽¹⁾ M1 ⁽²⁾	P50	P58	W2	V2	338
GND	P51	P59	GND ⁽⁴⁾	GND ⁽⁴⁾	-
MODE ⁽¹⁾ , M0 ⁽²⁾	P52	P60	Y1	W1	341
VCC	P53	P61	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
Not Connected ⁽¹⁾ PWRDWN ⁽²⁾	P54	P62	W3	V3	342 ⁽¹⁾
I/O, PGCK2 ⁽¹⁾ , GCK3 ⁽²⁾	P55	P63	Y2	W2	343 ⁽³⁾

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280 ^(2,5)	Bndry Scan
I/O (HDC)	P56	P64	W4	W3	346 ⁽³⁾
I/O	P57	P65	V4	T4	349 ⁽³⁾
I/O	P58	P66	U5	U4	352 ⁽³⁾
I/O	P59	P67	Y3	V4	355 ⁽³⁾
I/O (LDC)	P60	P68	Y4	W4	358 ⁽³⁾
I/O	-	-	-	R5	361 ⁽³⁾
I/O	-	-	-	U5	364 ⁽³⁾
I/O	P61	P69	V5	T5	367 ⁽³⁾
I/O	P62	P70	W5	W5	370 ⁽³⁾
I/O	P63	P71	Y5	R6	373 ⁽³⁾
I/O	P64	P72	V6	U6	376 ⁽³⁾
I/O	P65	P73	W6	V6	379 ⁽³⁾
I/O	-	P74	Y6	T6	382 ⁽³⁾
GND	P66	P75	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P67	P76	W7	W6	385 ⁽³⁾
I/O	P68	P77	Y7	U7	388 ⁽³⁾
I/O	P69	P78	V8	V7	391 ⁽³⁾
I/O	P70	P79	W8	W7	394 ⁽³⁾
VCC	P71	P80	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P72	P81	Y8	W8	397 ⁽³⁾
I/O	P73	P82	U9	U8	400 ⁽³⁾
I/O	-	-	V9	V8	403 ⁽³⁾
I/O	-	-	W9	T8	406 ⁽³⁾
I/O	-	P84	Y9	W9	409 ⁽³⁾
I/O	-	P85	W10	V9	412 ⁽³⁾
I/O	P74	P86	V10	U9	415 ⁽³⁾
I/O	P75	P87	Y10	T9	418 ⁽³⁾
I/O	P76	P88	Y11	W10	421 ⁽³⁾
I/O (INIT)	P77	P89	W11	V10	424 ⁽³⁾
VCC	P78	P90	VCC ⁽⁴⁾	VCC ⁽⁴⁾	VCC ⁽⁴⁾
GND	P79	P91	GND ⁽⁴⁾	GND ⁽⁴⁾	-
I/O	P80	P92	V11	T10	427 ⁽³⁾
I/O	P81	P93	U11	R10	430 ⁽³⁾
I/O	P82	P94	Y12	W11	433 ⁽³⁾
I/O	P83	P95	W12	V11	436 ⁽³⁾
I/O	P84	P96	V12	U11	439 ⁽³⁾
I/O	P85	P97	U12	T11	442 ⁽³⁾
I/O	-	-	Y13	W12	445 ⁽³⁾
I/O	-	-	W13	V12	448 ⁽³⁾
I/O	-	P99	V13	U12	451 ⁽³⁾
I/O	-	P100	Y14	T12	454 ⁽³⁾
VCC	P86	P101	VCC ⁽⁴⁾	VCC ⁽⁴⁾	-
I/O	P87	P102	Y15	V13	457 ⁽³⁾
I/O	P88	P103	V14	U13	460 ⁽³⁾
I/O	P89	P104	W15	T13	463 ⁽³⁾